

GAUSS INSTRUMENTS@the 2012 IEEE International Symposium on Electromagnetic Compatibility in Pittsburgh, Pennsylvania (US), 5th - 10th August 2012. Visit us at booth #923 together with our US distributor EMI Instrumentation and check out our TDEMI® Measurement System with its blazing speed in the frequency range 10 Hz to 40 GHz and its latest features, e.g. APD evaluation. Ultra high-speed measurements according to commercial and military standards up to 40 GHz boosting your EMC compliance and pre-compliance tests into new dimensions.

The unique combination of real-time analysis and full compliance allows to speed up scans by up to a factor of 4000. The weighted spectrogram mode allows to perform investigation and evaluation of non-stationary phenomena in real-time making the weighted spectrogram mode the ideal choice for online EMC debugging. In addition a classical single frequency mode is provided. The TDEMI® 40G and 26G Measurement Systems provide the CISPR bandwidths 200 Hz, 9 kHz, 120 kHz, 1 MHz as well as the bandwidths 10 Hz, 100 Hz, 1 kHz, 10 kHz, 100 kHz, 1 MHz for measurements according to military standards. The TDEMI® 1G - 18G can be upgraded with the Option MIL/DO-UG to fulfill the requirements of MIL 461F and DO160. The TDEMI® Measurement System allows to perform economic measurements according to CISPR 16-1-1, MIL 461F and DO160.

Visit us at booth #923 and have a look at the unique technology and blazing speed of the TDEMI® Measurement System from 10 Hz up to 40 GHz.

Have also a preview on novel research topics as well as a presentation of the technology of a system up to 40 GHz during the symposium conference session WED-PM-2 on Wednesday 08th of August in conference Room 301/302 (TC2) chaired by Don Heirmann and Robert Hofmann. The contributed scientific papers are entitled in detail

- A Novel Vector Near-Field Scanning System for Emission Measurements in Time-Domain
- A Broadband, Low-Noise Time-Domain System for EMI Measurements trough Ka-Band up to 40 GHz

More detailed information on the presented topics are available in the [final symposium program](#) on page 35. So come and take the chance to learn about the latest developments in the complex world of EMC testing and how to benefit by applying new methods to analyze electromagnetic interference in real-time and reduce measurement uncertainty.

Go to conference website for more information: <http://www.emc2012.org/>